

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
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Examiner		Art Unit		Page 1 of 1
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NON-PATENT DOCUMENTS

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	U	Plug & Play IDDQ Monitoring with QTG, K. Baker et al., 1995, IEEE
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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